

Search Notes

Application No.

10/696,835

Examiner

Christopher M. Keehan

Applicant(s)

WEI ET AL.

Art Unit

1712

SEARCHED

| Class | Subclass | Date | Examiner |
|-------|---------------|------------|----------|
| 252 | 405 | 12/13/2004 | CMK |
| | 588,589 | | |
| 424 | 70.1,70.2 | | |
| | 70.6,70.7 | | |
| | 70.9 | | |
| | 70.11 | | |
| | 70.12 | | |
| | 70.22 | | |
| | 70.27 | | |
| 524 | 86,104 105 | | |
| 528 | 342 | | |
| | 335 | | |
| | 332,336 | | |
| 525 | 421 | | |

INTERFERENCE SEARCHED

| Class | Subclass | Date | Examiner |
|---------|----------|------------|----------|
| same as | above | 12/13/2004 | CMK |
| | | | |
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**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

| | DATE | EXMR |
|----------------------|------------|------|
| EAST | 12/13/2004 | CMK |
| STN structure search | | |
| Inventor name search | | |
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